

# DTQ6D002-C www.din-tek.jp

## Dual N-Channel 100 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (mΩ)(Typ.)	I <sub>D</sub> (A)ª	Q <sub>g</sub> (Typ.)			
100	16.5 at V <sub>GS</sub> = 10 V	31	10.6nC			
100	21 at V <sub>GS</sub> = 4.5 V					

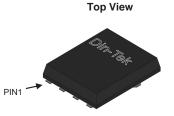
**DFN5X6-8L Pin Configuration** 

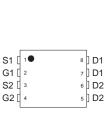
#### **FEATURES**

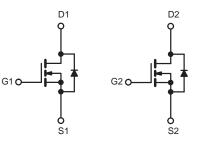
- DT-SJ Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested
- 100% Avalanche Test
- High Speed Power Switching

#### **APPLICATIONS**

- DC/DC in Telecoms and Inductrial
- Synchronous Rectification in SMPS
- · Hard Switching and High Speed Circuit







N1-Channel MOSFET

N2-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> ( $T_C = 25 \text{ °C}$ , unless otherwise noted)					
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V <sub>DS</sub>	100	V		
Gate-Source Voltage	V <sub>GS</sub>	± 20	v		
Continuous Drain Current (T <sub>1</sub> = 150 °C) <sup>a</sup>	T <sub>C</sub> = 25 °C	1-	31	A	
Continuous Drain Current (1) = 150°C)-	T <sub>C</sub> = 100 °C	I <sub>D</sub>	19		
Pulsed Drain Current <sup>b</sup>	I <sub>DM</sub>	120			
Single Avalanche Energy	E <sub>AS</sub>	40	mJ		
Maximum Power Dissipation <sup>c</sup>	T <sub>C</sub> = 25 °C	- Pn	36	W	
	T <sub>C</sub> = 100 °C	۳D	14		
Operating Junction and Storage Temperature R	ange	T <sub>J</sub> , T <sub>stg</sub>	-55 to + 150	°C	

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	LIMIT	UNIT		
Junction-to-Ambient (PCB Mount) <sup>d</sup>	R <sub>thJA</sub>	56	°C/W		
Junction-to-Case (Drain)	R <sub>thJC</sub>	3.5	C/W		

Notes

a. Calculated continuous current based on maximum allowablejunction temperature.

- b. Repetitive rating; pulse width limited by max. junction temperature.
- c. Pd is based on max. junction temperature, using junction-case thermal resistance.
- d. The value of ReuA is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with Ta=25 °C.



## DTQ6D002-C

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<b>SPECIFICATIONS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS}$ = 0 V, $I_D$ = 250 $\mu$ A	100	-	- \		
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, \ I_D = 250 \ \mu A$	1.2	-	2.5	v	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS}=0~V,~V_{GS}=\pm~20~V$	-	-	± 100	nA	
Zero Gate Voltage Drain Current		$V_{DS} = 100 V, V_{GS} = 0 V$	-	-	1	—μΑ	
Zero Gale Voltage Drain Gurrent	I <sub>DSS</sub>	$V_{DS}{=}80$ V, $V_{GS}{=}0$ V, $T_{J}{=}125$ °C	-	-	100		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	31	-	-	А	
Drain-Source On-State Resistance <sup>a</sup>	D	$V_{GS}$ = 10 V, $I_{D}$ = 20 A	-	16.5	20	mΩ	
Drain-Source On-State Resistance -	R <sub>DS(on)</sub>	$V_{GS}$ = 4.5 V, $I_{D}$ = 15 A	-	21	27		
Forward Transconductance <sup>a</sup>	<b>g</b> fs	$V_{DS} = 5 V, I_{D} = 20 A$	-	20	-	S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>		-	554	-	pF	
Output Capacitance	C <sub>oss</sub>	$V_{GS}$ = 0 V, $V_{DS}$ = 50 V, f = 1 MHz	-	258	-		
Reverse Transfer Capacitance	C <sub>rss</sub>		-	8.4	-		
Total Gate Charge <sup>c</sup>	Qg		-	10.6	-		
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{DS} = 50 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$	-	1.8	-	nC	
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>		-	2.5	-		
Gate Resistance	R <sub>g</sub>	f = 1 MHz	-	1.0	-	Ω	
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>		-	3.2	-		
Rise Time <sup>c</sup>	t <sub>r</sub>	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 20 A,	-	2.7	-		
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	$R_g = 3 \Omega, V_{GS} = 10 V$	-	10.5	-	ns	
Fall Time <sup>c</sup>	t <sub>f</sub>		-	4.0	-		
Drain-Source Body Diode Ratings and	Characteristi	ics <sup>b</sup> (T <sub>C</sub> = 25 °C)					
Continuous Source-Drain Diode Current	۱ <sub>S</sub>	T <sub>C</sub> = 25 °C	-	-	31	A	
Pulsed Current	I <sub>SM</sub>		-	-	120	А	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	$I_{F} = 2 A, V_{GS} = 0 V$	-	0.7	1.2	V	
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 20 A, di/dt = 100 A/µs	-	34	-	ns	
Reverse Recovery Charge	Q <sub>rr</sub>	$i_F = 20 \text{ A}, \text{ ai/dt} = 100 \text{ A/}\mu\text{S}$	-	39	-	nC	

Notes

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

c. Independent of operating temperature.

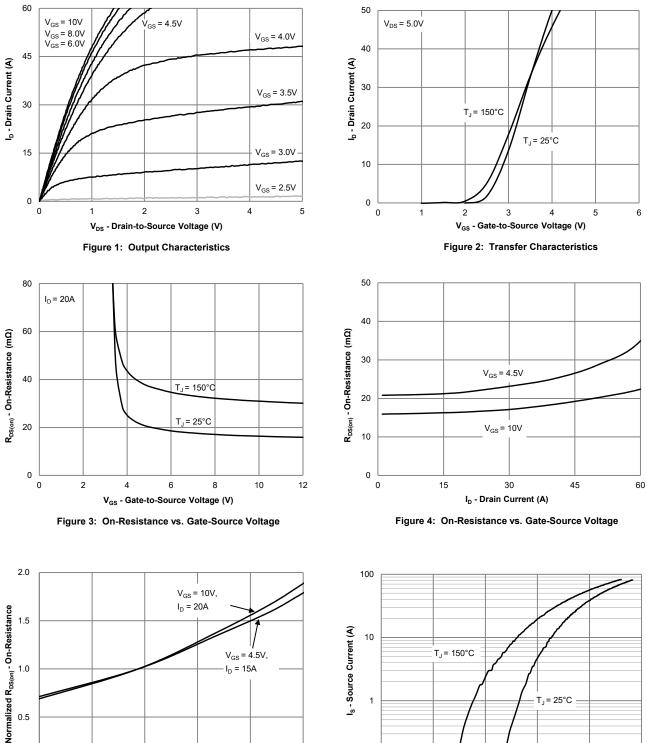
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those in dicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended pe riods may affect device reliability.



0.5

0.0 -50

#### TYPICAL CHARAC TERISTICS (25 °C, unless otherwise noted)



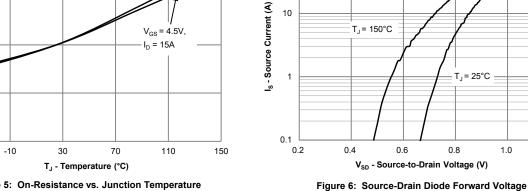


Figure 5: On-Resistance vs. Junction Temperature

3

1.2

T<sub>J</sub> = 25°C

1.0

0.8

0.4

0.6

V<sub>SD</sub> - Source-to-Drain Voltage (V)



#### TYPICAL CHARAC TERISTICS (25 °C, unless otherwise noted)

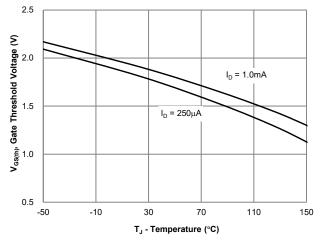
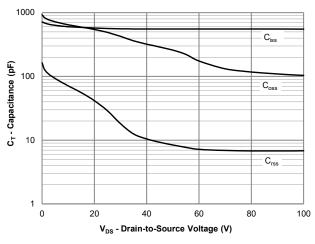
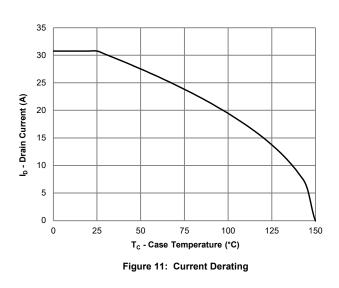


Figure 7: Gate Threshold Variation vs. Junction Temperature







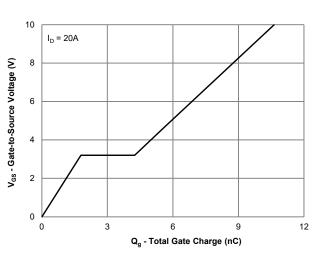


Figure 8: Gate Charge Characteristics

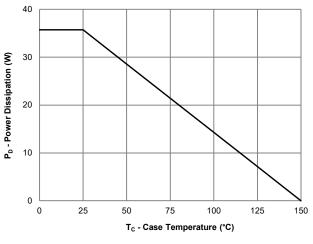
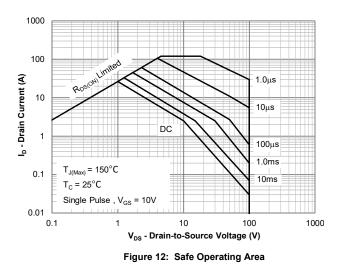


Figure 10: Power Derating





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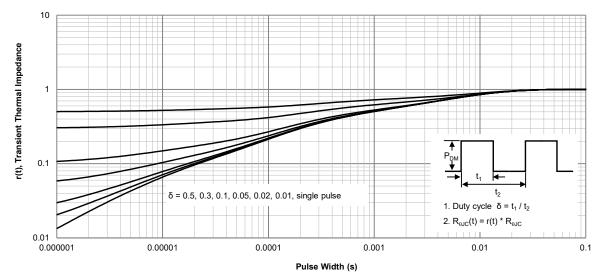
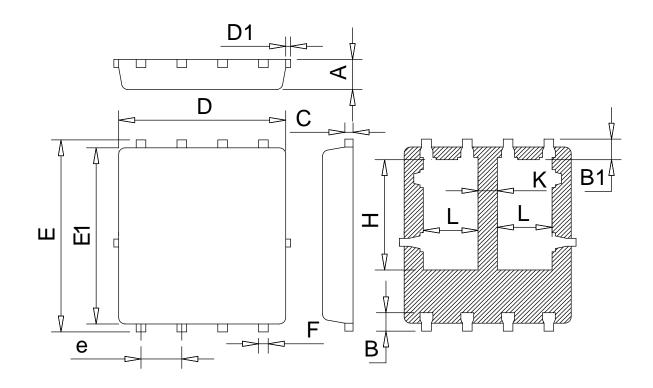


Figure 13: Normalized Maximum Transient Thermal Impedance



## **DFN5X6-8L-D PACKAGE OUTLINE**



### COMMON DIMENSIONS UNITS OF MEASURE=MILLIMETER)

Symbol	Min	Тур	Max
A	0.85	0.95	1.05
В	0.46	0.58	0.73
B1	0.52	0.65	0.78
С	0.18	0.254	0.32
D	4.70	5.20	5.50
D1	-	-	0.18
E	5.75	6.05	6.35
E1	5.35	5.65	5.85
е	1.15	1.27	1.50
F	0.15	0.30	0.50
Н	3.15	3.47	3.80
L	1.35	1.70	2.10
K	0.35	0.60	1.00



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